Interfacial Oxygen Vacancies as a Potential Cause of Hysteresis in Perovskite Solar Cells

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ABSTRACT: Organometal halide perovskite solar cells (PSCs) have emerged as one of the most promising photovoltaic technologies with efficiencies exceeding 20.3%. However, device stability problems including hysteresis in current–voltage scans must be resolved before the commercialization of PSCs. Transient absorption measurements and first-principles calculations indicate that the migration of oxygen vacancies in the TiO2 electrode under electric field during voltage scans contributes to the anomalous hysteresis in PSCs. The accumulation of oxygen vacancies at the electrode/perovskite interface slows down charge extraction while significantly speeding up charge recombination at the interface. Moreover, nonadiabatic molecular dynamics simulations reveal that the charge recombination rates at the interface depend sensitively (with 1 order of magnitude difference) on the locations of oxygen vacancies. By intentionally reducing oxygen vacancies in the TiO2 electrode, we substantially suppress unfavorable hysteresis in the PSC devices. This work establishes a firm link between microscopic interfacial structure and macroscopic device performance of PSCs, providing important clues for future device design and optimization.

INTRODUCTION

Organic/inorganic trihalide lead based perovskite materials have attracted worldwide attention for their promising potential in photovoltaic and optoelectronic applications.1–3 They have many desirable attributes such as low-cost, facile synthesis, high visible absorption, and long carrier diffusion lengths that are ideal for photovoltaic applications.4–6 In the past few years, tremendous efforts were carried out for the optimization of the devices, including the development of novel light-harvesting7,8 and carrier transport materials9,10 as well as the improvement of perovskite film quality via new synthetic methods.11–13 The state-of-the-art perovskite solar cell (PSC) incorporates either nanocrystalline or compact TiO2 to facilitate electron transport and to enhance long-term stability,14,15 accentuating the essential role of TiO2 layers. Recently, the PSC with a novel light-harvesting layer has reached a record efficiency of 20.3%,16 approaching that of thin film CdTe and CuInGaSe2 solar cells.

Despite significant progress, critical problems remain to be resolved before PSCs could enter the marketplace. In particular, anomalous hysteresis and device stability are among the most challenging issues. It has been observed that the perovskite devices exhibit significant hysteresis during opposite voltage scanning directions, casting doubts on the reliability and stability of this technology. The hysteresis exists in both planar device structure and those with mesoporous scaffolds.17 The hysteresis is strongly influenced by the scanning rate and the perovskite crystal size.18,19 Using piezoforce microscopy, Padture et al. directly observed ferroelectric domains induced by CH3NH3+ in high-quality CH3NH3PbI3 thin films and demonstrated its contribution to the hysteresis.20 Walsh et al. established a link between ferroelectric domains and hysteresis by using first-principles modeling.21 However, it is under heavy debate whether ferroelectricity is related to hysteresis, mainly due to its incomparable time scale with the operation time of devices.22–25 Now many works believe trap states or ion migration of perovskite are responsible for hysteresis. For
example, by fullerene passivation in planar PSCs, Huang et al. and Sargent et al. were able to eliminate hysteresis. It was hence speculated that defects in perovskite lattice and surface could trap carriers, leading to hysteresis. More serious hysteresis was observed after applying constant electric field to PSC devices. The switchable photovoltaic effect was explained by ion migration within the perovskite layer. Recently, Snaith et al. showed theoretically that both ion migration and electronic charge traps, serving as recombination centers, were responsible for adverse hysteresis in PSC. The paper does not explain the details of mobile ions or carrier traps. By doping zirconium or lithium into the TiO2 electrode, Ginger et al. and Im et al. improved the power conversion efficiency (PCE) and suppressed hysteresis of perovskite solar cells. The interfacial oxygen vacancies are identified as one of the microscopic origins of anomalous hysteresis, which have been largely ignored up to now. More importantly, we show that the hysteresis can be suppressed by reducing the interfacial oxygen vacancies.

**RESULTS**

Controlling Oxygen Vacancy Density. Previous works have shown that defects in bulk and perovskite surface could trap carriers, giving rise to anomalous hysteresis in TiO2 PSCs. Here we find that oxygen vacancies (V_O) in electron transport layer TiO2 have the same detrimental effect. First of all, a link between V_O and hysteresis should be confirmed. A straightforward way is to control the VO density and see whether the hysteresis of PSCs is influenced. In this work, we intentionally manipulated VO density in TiO2 mainly by annealing it in different atmosphere or by plasma treatment. The existence of oxygen vacancies in treated TiO2 can be characterized by UV–vis absorption spectra and XRD. Here we adopt the TiO2 single crystal as a simple model. For TiO2 without any treatment, it has an optical bandgap of 3 eV. Therefore, it cannot absorb visible light (Figure 1a,b). When oxygen vacancies are introduced into TiO2, electrons trapped in localized states within the bandgap can be excited to the conduction band, leading to strong absorption in the visible range (Figure 1a,b).
However, when Vo density is low, UV–vis absorption measurement cannot distinguish the difference between TiO\textsubscript{2} treated in high oxygen pressures from PO\textsubscript{2} = 0.03 to 0.2 atm by heating at 900 °C for 24 h (PO\textsubscript{2} is defined as oxygen partial pressure, 1 atm =1.01 × 10\textsuperscript{5} Pa). Figure 1b shows an example for TiO\textsubscript{2} annealed in P\textsubscript{O}\textsubscript{2} = 0.1 atm (green curve). Its absorption spectrum nearly overlaps with TiO\textsubscript{2} perfect crystal without any treatment.

We apply XRD to distinguish the small differences between TiO\textsubscript{2} substrates upon heat treatments under different P\textsubscript{O}\textsubscript{2}. The XRD patterns for TiO\textsubscript{2} treated under different P\textsubscript{O}\textsubscript{2} are shown in Figure 1 (Figure 1c for wide angle XRD and Figure 1d is an enlarged view of Figure 1c between 27.0° and 28.0°). From Figure 1c we find that all the samples exhibit pure rutile phase, suggesting that oxygen doping does not change the phase of TiO\textsubscript{2}. The peak at about 27.4° is assigned to the rutile (110) diffraction. There is an obvious shift in the peak position, which indicates that there is a change in the spatial separation distance between neighboring TiO\textsubscript{2} (110) lattice planes. Using the Bragg equation, the (110) crystal plane spacing is calculated to be enlarged from 3.242 to 3.262 Å with oxygen pressure decreasing from 0.2 to 0.03 atm. It has been reported that oxygen removal lead to repelling between nearest Ti cations and the increase in lattice spacing.\textsuperscript{36,37} Our result is in good accordance with this trend.

Figure 1d shows that a large amount of oxygen vacancies naturally exist in commercial TiO\textsubscript{2} single crystals without any treatment (black curve). Natural TiO\textsubscript{2} single crystal roughly corresponds to the samples treated at an oxygen pressure of ∼0.1 atm. After annealing in P\textsubscript{O}\textsubscript{2} = 0.2 atm atmosphere, VO sites can be partly filled. The VO reduction or addition can be also characterized by electrical conductivity measurement. Resistivity of commercial TiO\textsubscript{2} is determined to be 9.3 × 10\textsuperscript{3} Ω·m by four-probe measurement. The value for TiO\textsubscript{2} (P\textsubscript{O}\textsubscript{2} = 0.02 atm) is 8.6 × 10\textsuperscript{3} Ω·m, indicating effectively n-type doping. For TiO\textsubscript{2} annealed at 0.2 atm oxygen pressure, its resistivity is beyond the measurement range, much higher than the above two cases. The result matches well with previous work,\textsuperscript{38} suggesting that the Vo density can be controlled intentionally.

**Influence of Oxygen Vacancies on Device Hysteresis.**

Inspired by the fact that oxygen vacancies in TiO\textsubscript{2} can be controlled, we move to the second step to see whether the hysteresis of PSCs can be influenced by V\textsubscript{o} density. Figure 2a
shows a typical structure of the mesoporous perovskite solar cell (PSC) devices. The TiO2 nanocrystalline film is doped with oxygen vacancies by sintering the film at 500 °C in different oxygen atmosphere. Although the lower annealing temperature is adopted here, XRD confirms the crystal lattice changes for the treated nanocrystalline TiO2 (Figure S1). The higher the oxygen pressure, the lower the VO density would be resulted.

**Table 1. Performance Characteristics of Perovskite Solar Cells Based on Nanocrystalline TiO2 with Different VO Densities**

<table>
<thead>
<tr>
<th>cell</th>
<th>oxygen pressure (atm)</th>
<th>sweep direction</th>
<th>$V_{oc}$ (V)</th>
<th>$J_{sc}$ (mA/cm²)</th>
<th>FF</th>
<th>$\eta$ (%)</th>
<th>hysteresis index</th>
</tr>
</thead>
<tbody>
<tr>
<td>#1</td>
<td>no treatment</td>
<td>FS*</td>
<td>0.90</td>
<td>9.6</td>
<td>0.67</td>
<td>5.8</td>
<td>2</td>
</tr>
<tr>
<td></td>
<td></td>
<td>RS</td>
<td>0.87</td>
<td>7.2</td>
<td>0.46</td>
<td>2.9</td>
<td></td>
</tr>
<tr>
<td>#2</td>
<td>0.02</td>
<td>FS</td>
<td>0.89</td>
<td>10.0</td>
<td>0.54</td>
<td>4.8</td>
<td>1.85</td>
</tr>
<tr>
<td></td>
<td></td>
<td>RS</td>
<td>0.89</td>
<td>8.1</td>
<td>0.35</td>
<td>2.6</td>
<td></td>
</tr>
<tr>
<td>#3</td>
<td>0.03</td>
<td>FS</td>
<td>0.93</td>
<td>8.5</td>
<td>0.64</td>
<td>5.0</td>
<td>1.43</td>
</tr>
<tr>
<td></td>
<td></td>
<td>RS</td>
<td>0.93</td>
<td>7.6</td>
<td>0.50</td>
<td>3.5</td>
<td></td>
</tr>
<tr>
<td>#4</td>
<td>1</td>
<td>FS</td>
<td>0.88</td>
<td>9.3</td>
<td>0.54</td>
<td>4.5</td>
<td>1.18</td>
</tr>
<tr>
<td></td>
<td></td>
<td>RS</td>
<td>0.93</td>
<td>8.5</td>
<td>0.48</td>
<td>3.8</td>
<td></td>
</tr>
</tbody>
</table>

*FS: forward scan, from $V_{oc}$ to $J_{sc}$*  
*RS: reverse scan, from $J_{sc}$ to $V_{oc}$*

**Table 2. Performance Characteristics of Planar Perovskite Solar Cells Based on Compact TiO2 with Different Plasma Treatments**

<table>
<thead>
<tr>
<th>cell</th>
<th>treatment</th>
<th>sweep direction</th>
<th>$V_{oc}$ (V)</th>
<th>$J_{sc}$ (mA/cm²)</th>
<th>FF</th>
<th>$\eta$ (%)</th>
<th>hysteresis index</th>
</tr>
</thead>
<tbody>
<tr>
<td>#5</td>
<td>no treatment</td>
<td>FS*</td>
<td>0.79</td>
<td>23.4</td>
<td>0.57</td>
<td>10.58</td>
<td>1.66</td>
</tr>
<tr>
<td></td>
<td></td>
<td>RS</td>
<td>0.66</td>
<td>23.4</td>
<td>0.41</td>
<td>6.39</td>
<td></td>
</tr>
<tr>
<td>#6</td>
<td>Ar plasma</td>
<td>FS</td>
<td>0.74</td>
<td>11.3</td>
<td>0.49</td>
<td>4.07</td>
<td>5.34</td>
</tr>
<tr>
<td></td>
<td>plasma</td>
<td>RS</td>
<td>0.51</td>
<td>6.6</td>
<td>0.23</td>
<td>0.76</td>
<td></td>
</tr>
<tr>
<td>#7</td>
<td>O₂ plasma</td>
<td>FS</td>
<td>0.80</td>
<td>23.4</td>
<td>0.57</td>
<td>10.63</td>
<td>1.63</td>
</tr>
<tr>
<td></td>
<td>plasma</td>
<td>RS</td>
<td>0.65</td>
<td>23.7</td>
<td>0.42</td>
<td>6.53</td>
<td></td>
</tr>
</tbody>
</table>

*FS: forward scan, from $V_{oc}$ to $J_{sc}$*  
*RS: reverse scan, from $J_{sc}$ to $V_{oc}$*

Figure 3. (a) Stabilized current−voltage ($I−V$) curves for perovskite solar cells with TiO2 compact layer treated by plasma, measured under AM 1.5G (100 mW/cm²) illumination. Arrows represent scanning direction. (b) Power conversion efficiency as a function of time for the same cell in (a) held close to maximum power point forward bias.

TiO2 samples. As a result, efficiency of cells with modified TiO2 decreased to be ~5% (highest value, see Table 1). The reduction can be explained by the appearance of larger size of nanoparticles and undesirable three-dimensional assembly of nanoparticles. Insets in Figure 2c−f show that TiO2 nanoparticles grow to be over 100 nm after annealing, much larger than P25. These planar-like devices have lower efficiency than cell #1 under our experimental conditions.

The hysteresis index is defined as $\eta_{forward}/\eta_{reverse}$. In Table 1, hysteresis index values are listed together with photovoltaic parameters depending on scan direction. For devices with larger amounts of $V_O$ ($P_{O_2} = 0.02$ atm), they show larger hysteresis index of 1.85 compared with those ($\eta_{reverse}/\eta_{forward} = 1.18$) with less $V_O$ ($P_{O_2} = 1$ atm). It is noted that $I−V$ hysteresis becomes less pronounced as the $V_O$ density decreased. Since parameters of all devices were controlled to be the same except cell #1 with smaller TiO2 crystalline size, it is reasonable to attribute the reduced hysteresis to less VO sites within TiO2. Interestingly, cell #1 with P25 TiO2 also shows severe hysteresis. Compared
with cell #4, it is clear that we almost eliminate hysteresis by reducing VO amounts in TiO₂.

To avoid the complex structure of mesoporous TiO₂ layer, we also investigate the effect of VO on hysteresis in planar PSCs. In this type of device, the mesoporous TiO₂ layer is removed. Oxygen vacancies in the compact TiO₂ layer were produced (reduced) by Ar (O₂) plasma, which is well-known as a surface treatment technique. The performance of planar PSC devices is shown in Figure 3 and Table 2, together with their hysteresis index listed.

When compact TiO₂ without any treatment is applied in the PSC device, the device reaches an efficiency of η = 10.58% (forward scan, cell #5), and its efficiency is stabilized at ~8.9% under one sun illumination (Figure 3b). For cell #6, VO density in TiO₂ is increased by Ar plasma treatment, confirmed by XRD (Figure S2). It is obvious that efficiency of cells with a high density of VO dramatically decreases to 4.07%, with much larger hysteresis index (5.34) compared to cell #5 (1.66). More importantly, its maximum power output undergoes a fast decay in less than 10 s, suggesting a detrimental effect of oxygen vacancies. For cell #7, its VO density is reduced by O₂ plasma, leading to a slightly higher efficiency (forward scan, 10.63%) and lower hysteresis index (1.63). The real efficiency of cell #7 is determined to be 9.3% by stabilized power measurement (Figure 3b). Comparing cell #7 with #5, it is clear that the removal of oxygen vacancy at TiO₂ surface improve the device performance.

All planar PSCs show larger hysteresis than their mesoporous counterparts, which can be easily understood by insufficient charge extraction of TiO₂. Still, performance of planar perovskite solar cell strongly proves that VO in TiO₂ is a potential cause of hysteresis, which is the same as mesoporous cells.

Ultrafast Charge Dynamics between Perovskite and TiO₂. The role of these VO sites in TiO₂ can be investigated by transient absorption (TA) and time-resolved PL measurement. Perovskite CH₃NH₃PbI₃ film was deposited on single-crystal TiO₂ substrate pretreated with different VO densities. In TA measurement, pulse with a wavelength of 826 nm (1.5 eV)was used to excite electrons in perovskite and its response to 413 nm light was shown in Figure 4a. Fitting the kinetics for the transient absorption signal of light at 413 nm shows a time constant of 10−20 ps. The decay behavior originates from photoexcited electrons in perovskite conduction band, judging from the measured ultrafast time scale.

Table 3. Kinetic Parameters for Electron Injection from Perovskite to Different TiO₂ Substrates Measured by TA Setup

<table>
<thead>
<tr>
<th>substrate</th>
<th>TiO₂ (O₂ 0.2 atm)</th>
<th>TiO₂ (O₂ 0.1 atm)</th>
<th>TiO₂ (O₂ 0.03 atm)</th>
<th>Al₂O₃</th>
</tr>
</thead>
<tbody>
<tr>
<td>τ (ps)</td>
<td>11</td>
<td>13</td>
<td>20</td>
<td>∼ 20</td>
</tr>
</tbody>
</table>

at more than 10 points and average the time constants in Table 3. Low oxygen pressure during annealing leads to more oxygen vacancies. It is clear that slower injection rates result from more oxygen vacancies. For TiO₂ with a large amount of VO sites (Pₐ₀ = 0.03 atm), the time constant is even comparable with that of perovskite/Al₂O₃ (Figure 4a).

Time-resolved PL has been performed to investigate the carrier recombination rate at CH₃NH₃PbI₃/TiO₂ interface. Figure 4b shows the PL decay curve of perovskite on different substrates. The instrumental response curve has already been cut off. Fitting the decaying signal with double exponential function gives 13 and 71 ns time constant for CH₃NH₃PbI₃/Al₂O₃ heterointerface (black curve). The faster component is attributed to recombination at grain boundaries as shown in Figure 4a and Table 3 show the influence of VO density on charge injection rate. For each case, we measure transient signal...
thicknesses on all substrates are 200 ± VO-d and VO-e are 3-fold coordinated. We note that the TiO2

The 71 ns process is designated to be the intrinsic lifetime of photo excited carriers, which is shorter than previously reported values due to the differences in experimental setup.

Table 4. PL Lifetime of Perovskite on Different Substrates

<table>
<thead>
<tr>
<th>Substrate</th>
<th>LAO</th>
<th>TiO2 (O2 0.2 atm)</th>
<th>TiO2 (O2 0.1 atm)</th>
<th>TiO2 (O2 0.05 atm)</th>
<th>TiO2 (O2 0.05 atm)</th>
<th>TiO2 (O2 0.02 atm)</th>
</tr>
</thead>
<tbody>
<tr>
<td>τ (ns)</td>
<td>71</td>
<td>32.7</td>
<td>32</td>
<td>28.6</td>
<td>27.2</td>
<td>24.6</td>
</tr>
</tbody>
</table>

Figure 5. (a) Atomic structure of perovskite/TiO2 rutile (110) interface. a, b, c, d, and e show five different atomic sites of oxygen vacancy in the TiO2 substrate. a, b, and c are stable. d transfers to a during the structural optimization, whereas e transfers to c during the MD. (b−e) Projected density of states (PDOS) of TiO2/perovskite with V0 located at different sites in TiO2. The gray shadowed region shows the density of states for TiO2 substrate, the red lines denote the density of states for perovskite layer, while the blue lines are the defect states of oxygen vacancies in TiO2.

Effects of Oxygen Vacancies on Electron Transfer using NAMD Simulations. To give a deeper insight into how oxygen vacancies of TiO2 influence macroscopic hysteresis in current−voltage (I−V) scans, we investigate the effects of V0 on interfacial electron injection and electron−hole recombination using the fewest-switching-surface-hopping (FSSH) NAMD simulations.

The FSSH method is based on the hypothesis that the time evolution of a wave packet through a potential-energy branching region can be approximated by an ensemble of independent semiclassical trajectories stochastically distributed among the branched surfaces. Electronic redistribution is achieved by allowing electronic hops between the potential energy surfaces according to a certain probability distribution determined by the nonadiabatic couplings.

In line with the experiments, we have placed a sheet of perovskite (containing 84 atoms) on top of the rutile TiO2 (110) surface (with 96 atoms in six-atomic layers) to model the perovskite/TiO2 heterointerface (Figure 5a). Five different sites of V0 (a, b, c, d, and e) at the interface between the perovskite/ TiO2 are considered (Figure 5a). The oxygen atoms in V0-a and V0-c are 2-fold bridging, whereas oxygen atoms in V0-b, V0-d, and V0-e are 3-fold coordinated. We note that the TiO2 slab adopted here is thin, containing only surface and subsurface oxygen vacancies which are sufficiently close to the perovskite/TiO2 interface or to TiO2 surface. Although the thicker TiO2 slab could be used in principle to obtain concrete data, it brings huge computational cost unaffordable in the present work.

To justify the choice of our relatively thin TiO2 slab model, we compare carefully our results with those reported in literature obtained with considerably thicker TiO2. The calculated formation energy for the surface (site c here) and subsurface (site b) oxygen vacancy is 3.39 and 3.44 eV, respectively. These numbers are fairly close to those reported by Selloni et al., where surface VO (site c) has the lowest formation energy. Within the energy difference between surface and subsurface oxygen vacancies is 310 meV, which is even lower than that for VO diffusion from TiO2 surface to the bulk (0.6−0.7 eV), thanks to the interface bonding between TiO2 and the perovskite. Nevertheless, VO diffusion could occur in both thin and thick TiO2 slab models.

In addition, because we focused on electron dynamics of perovskite/TiO2 heterointerface here, only the oxygen vacancies near interface are crucial for electron injection and electron−hole recombination at interface. Therefore, we believe the model of perovskite/TiO2 layer adopted here is plausible to capture the essential physics for interface interactions and yield reasonable results.

We found oxygen vacancies at a, b, and c sites are stable (during both structural optimization and molecular dynamics simulations). In contrast, strongly affected by the interactions between perovskite and TiO2 layer, oxygen vacancy at d and e sites are not stable: V0-d is not a minimum on the potential energy surface, changing to V0-a during structural optimization; although V0-e is stable after structural relaxation, it turns into V0-c during heating from 0 to 300 K in MD simulations. The site c is the most stable one with the vacancy formation energy...
of 50 meV lower than that at the site b. The site a is the least stable one with the formation energy 190 meV higher than b.

It is well-known that point defects in a semiconductor can introduce defect states in the band gap. For TiO2 with oxygen vacancies, an occupied defect level slightly below the TiO2 conduction band edge is formed (Figure 5b-5e, \(\Delta E = 0.17\) eV for V\(_{O-a}\), 0.58 eV for V\(_{O-b}\), and 0.69 eV for V\(_{O-c}\)), corresponding to a donor state. The shallow donor state introduced by the V\(_O\) has been observed previously.\(^{52\text{--}54}\)

Although this donor state is occupied at the ground state, the excited electrons can relax back to the donor state. Although this donor state is occupied at the ground state, the excited electrons can relax back to the donor state.

Then we investigate the influence of different V\(_O\) densities on interfacial electron injection and electron–hole recombination. Several vacancy concentrations, including 0%, 1.6% (1 V\(_O\) in the simulation cell), 3.2%, and 4.8% are studied. Figure 6a shows the fraction of electrons injected from the perovskite to TiO2 conduction bands in the presence of different oxygen vacancies concentration. By an exponential fit, the injection time scale is estimated as 3.83 fs for V\(_O\) density of 0%, 5.71 fs for 1.6%, 7.99 fs for 3.2%, and 11.14 fs for 4.8%. With the increase of the vacancy concentration, the electron injection rate decreases. The recombination dynamics for the different vacancy densities is shown in Figure 6b. As more oxygen vacancies introduce more electronic trap states, a dramatic increase in the charge recombination (or the electron back-transfer from TiO2 conduction bands to the perovskite) rate. By a linear extrapolation, one can estimate the time scale for which all electrons are transferred back to the perovskite, defined as the time scale for the charge recombination. The time scale for recombination is estimated to be 46.59 ps for 0%, 13.65 ps for 1.6%, 5.16 ps for 3.2%, and 3.74 ps for 4.8%. Our computation results agree well with experimental data, that increasing the V\(_O\) densities in TiO2 layer would introduce charge traps for interface electron transfer, thus significantly blocking electron injection from perovskite to TiO2 substrate and dramatically facilitating charge recombination at the heterointerface. The difference in absolute values between theory and experiment is a result of ultrathin film thickness (~1 nm) and idealistic interface geometry assumed in theoretical modeling, while in experiments the electrons have to travel through much thicker perovskite film (~200 nm).

However, the above discussions can only demonstrate that V\(_O\) concentrations do affect the overall efficiency of PSC; why and how the densities of defects impact the adverse hysteresis are still unknown and need to be further explored. So we make further investigation on the influence of different V\(_O\) sites on interface charge transfer at perovskite/TiO2 heterojunction. As shown in Figure 6c, compared with the perfect perovskite/TiO2 interface (black line in Figure 6c), introducing of oxygen vacancies slightly slow down the electron injection dynamics across the interface (3.83 fs for the perfect TiO2, 3.97 fs for the vacancy at site a, 5.71 fs at site b, and 5.35 fs at site c). When the position of V\(_O\) moves far away from interface, photoexcited electron transfer from perovskite to TiO2 gradually slows down. The recombination dynamics for the different vacancy sites is shown in Figure 6d. V\(_O\) induced trap states dramatically accelerate back electron transfer from TiO2 conduction bands to the perovskite. The recombination lifetime is strongly related to different V\(_O\) sites (46 ps for the intact TiO2, 1 ps for site a, 14 ps for site b, and 10 ps for site, respectively. Note that the oxygen vacancy in site c is more like a surface vacancy (at TiO2/vacuum interface), and therefore, the injection and recombination dynamics for site c might be different from the interface electronic dynamics of defects in deeper layer. However, the results for interface site a and subsurface site b is still meaningful. Therefore, faster electron–hole recombination

![Figure 6](https://chem.mater.2016.28.802-812)

**Figure 6.** (a) Electron transfer fraction (\(\chi\)) from the perovskite to the TiO2 conduction bands as a function of time for different densities of V\(_O\) in TiO2. (b) Electron transfer as a function of time during the recombination process for different densities of V\(_O\) in TiO2. (c) Electron transfer fraction from the perovskite to the TiO2 conduction bands as a function of time for intact TiO2 and TiO2 with V\(_O\) at different sites. (d) Electron transfer as a function of time during the recombination process for intact TiO2 and TiO2 with different V\(_O\) sites.
takes place when $V_O$ sites are located near the interface of heterojunction.

As the oxygen vacancies may migrate under the external electric field during the voltage scans, different interfacial charge transfer and recombination rates may occur depending on the location of the vacancies. We thus infer that the oxygen vacancies could be one important origin of the anomalous hysteresis frequently observed in PSCs.

### DISCUSSION

To verify this conjecture, we look back at PSC performance in Figure 2 and Figure 3. It is interesting to note that $\eta_{\text{forward}}$ is lower than $\eta_{\text{reverse}}$ in all cases, which is reasonable according to the above discussions. When the scan starts from $V_{\text{oc}}$, an external electric field pointing from perovskite layer to TiO$_2$ film is applied on the photovoltaic device, oxygen vacancies are thus transferred from perovskite/TiO$_2$ interface to deeper layers of TiO$_2$, leading to a relatively slower recombination rate, therefore resulting in a higher power output. We note that the kinetic barrier for $V_O$ migration in TiO$_2$ is 0.6–0.7 eV, which can be overcome at room temperature. The directed diffusion of $V_O$ toward or away from the interface region can be expected with the assistance of external electric field. When the scan starts from $I_{sc}$, an inverse electric field is applied, driving the oxygen vacancies transfer to the heterointerface, bringing about a faster interface recombination dynamics and generating worse power output. Based on this explanation, it is natural to deduce that less oxygen vacancies could lead to a more balanced device performance when the scanning direction is concerned.

The carrier trapping and detrapping mechanism also give us invaluable insight into the relationship between the $V_O$ density and the hysteresis in PSC. Dynamic measurement and simulation have demonstrated that the presence of interfacial oxygen vacancies lead to carrier trapping for electrons flowing from perovskite to TiO$_2$. The explanation is valid for both single crystal and nanocrystalline TiO$_2$ (Figure S4). These traps are filled under forward bias working conditions, while they are emptied out under short-circuit conditions due to facile charge transfer to TiO$_2$, leading to poor operation until the traps are filled again. The slow emptying and filling of traps ($\sim 0.01$ s at room temperature) is consistent with the long time scale of $I$–$V$ curve measuring.

Above discussion suggests that the reduction of oxygen vacancies in TiO$_2$ can effectively suppress unfavorable $I$–$V$ hysteresis of perovskite devices. In this work, the $V_O$ sites act as traps for electrons injected from perovskite, facilitate charge recombination, and result in severe hysteresis. On the other hand, the presence of $V_O$ sites improves the conductivity of TiO$_2$ as confirmed in electrical transport measurement. Therefore, a good balance must be retained between improved interfacial charge transfer efficiency and damaged transport in bulk. According to simulation result, $V_O$ at TiO$_2$/perovskite interface contributes more to hysteresis. Therefore, these $V_O$ sites should be eliminated while bulk oxygen vacancy should be preserved to maintain the conductivity, as shown by O$_2$ plasma treated planar devices (Figure 3).

And it should be noted that dye-sensitized solar cell (DSC), which also applies TiO$_2$ as electron transport layer, does not exhibit hysteresis. The controversy can be explained by different coverage of the light absorber layer. In the PSC device, the perovskite nanocrystal contacts well with TiO$_2$ surface atom by atom (Figure 5a), while less than 10% surface atoms are linked to dye molecules in DSC. Based on this fact, we believe oxygen vacancy has a much larger effect in PSC than in DSC devices. A unique merit in the present work is that the stable performances in PSC devices are directly linked to the microscopic interface atomistic structures and electronic features at the perovskite/TiO$_2$ interface.

### CONCLUSIONS

We present a combined spectroscopic and computational study on hysteresis phenomenon in perovskite solar cells. The oxygen vacancies in TiO$_2$ trap photoexcited electrons and migrate under electric field, resulting in different injection and recombination dynamics at interface, thus leading to unfavorable hysteresis. Annealing the nanocrystalline TiO$_2$ at 1 atm oxygen partial pressure or pretreating TiO$_2$ by O$_2$ plasma effectively fill the original $V_O$ sites and suppress the $I$–$V$ hysteresis. We expect that our method is valid even after further optimization of PSC devices. The approaches such as applying constant electric field or annealing TiO$_2$ at controlled temperature will be employed to manipulate the location of oxygen vacancies, which may enhance and stabilize the device photovoltaic performance in a more precise way. The present study on the relationship between interfacial defects and photovoltaic performance provides new insights toward a complete understanding of perovskite solar cell working mechanisms at the microscopic scale.

### METHODS

**Perovskite Film Deposition.** Perovskite film (doped with chlorine) was prepared by the following processes. First, rutile TiO$_2$ single crystals (Hefei Ke Jing Materials Technology Co., Ltd) were cleaned by acetone, deionized water, and ethanol. Then they were subjected to an O$_3$/ultraviolet treatment for 10 min. Following the cleaning procedure, TiO$_2$ crystals were coated with PbI$_2$/PbCl$_2$ by spin coating 0.5 M PbI$_2$ (99.999%, Aldrich) and 0.1 M PbCl$_2$ (99.999%, Aldrich) in N,N-dimethylformamide (99.7%) at 4500 r.p.m. for 60 s and dried at 100 °C for 15 min. For transient absorption measurement, the concentration of PbI$_2$/PbCl$_2$ was reduced to be one-fifth. After that, perovskite was made by spin coating a solution of CH$_3$NH$_3$I (Dyeno) in 2-propanol (10 mg/mL) at 1200 r.p.m. for 6s and 4500 r.p.m. for 60 s on PbI$_2$ film and dried at 100 °C for 10 min.

**Perovskite Solar Cell Fabrication.** FTO glasses were cleaned by sequential sonication in distilled water, acetone, and ethanol, and then treated in UV-Ozone cleaner for 15 min. To make the compact TiO$_2$ blocking layer, cleaned FTO glasses were coated with 0.15 M titanium tetraisopropanolate in ethanol by spin-coating method at 3000 r.p.m. for 60 s. The film was heated at 500 °C for 2 h. After the coated film was cooled to room temperature, the same process was repeated once. On the prepared dense TiO$_2$ layer, the nanocrystalline TiO$_2$ paste was deposited by a spin coating method, and the deposited film was annealed at 500 °C for 0.5 h. Thicknesses of the TiO$_2$ films were controlled to be 200 nm. Perovskite film was fabricated by a two-step deposition method. The parameters are the same as above. The hole transport material (HTM) consists of 67.7 mg of spiro-MeOTAD, (Luminescence Technology), 8.5 mg of bis(trifluoromethane) sulfonimide lithium salt (LiTFSI, 99.95%, Aldrich) and 0.027 mL of 4-tert-butylpyridine (TBP, 96%, Aldrich) in 1 mL of mixed solvent of...
chlorobenzene (99.7%) and acetonitrile (99.7%) (chlorobenzene:acetonitrile 20:1 v/v). The perovskite/TiO₂ films were coated with HTM solution using spin-coating method at 4000 r.p.m. for 30 s. For the counter electrode, 80 nm-thick Au film was deposited on the top of the HTM by thermal evaporation under 6 × 10⁻⁴ Pa vacuum. The device active area is 0.1 cm².

To fabricate planar perovskite solar cells, compact TiO₂ on FTO glasses are treated by Ar plasma for 3 min or O₂ plasma for 2 min (90 W). Then high-quality perovskite films were fabricated in a glovebox with well controlled humidity. Substrates were coated by spin coating 0.8 M PbCl₂ and 2.5 M CH₃NH₃I in N₂,N-dimethylformamide at 2500 r.p.m. for 30 s and dried sequentially at 60 °C for 60 min, 100 °C for 50 min and 105 °C for 30 min.

Oxygen Vacancy Characterization. Oxygen vacancies were added or reduced by heating the single crystal at 900 °C for 24 h at an oxygen pressure of 0.02–1.0 atm. For the nanoparticle TiO₂ applied in devices, the annealing temperature was kept at 500 °C to avoid phase transformation. They were characterized by UV–vis absorption spectra and X-ray diffraction (XRD). Absorption spectra were measured by SpectraPro-500i UV–vis spectrometer. XRD patterns were collected on a Rigaku Smartlab 9000 X-ray diffractometer (Cu Ka) in the range of 10°–80°.

Ultrafast Dynamics Measurement. Dynamic measurements were carried out to characterize the electron injection and recombination process by using the femtosecond transient absorption setup (fs-TA) and time-resolved photoluminescence (PL) setup, respectively. For measuring charge injection dynamics with the fs-TA, a titanium/sapphire laser (Coherent, Ultra II) with a repetition rate of 80 MHz, and a pulse width of 150 fs was employed. The beam was separated into two parts. One part was used as the pump pulse to excite the sample. The other part was used to pass through a BaB₂O₄ crystal to generate light pulses with double frequency. In this study, 826 nm light (1.5 eV) was used for pumping and 413 nm (3.0 eV) for probing. Transmission spectrum difference ΔT at 413 nm between excited and ground state sample was recorded. Although 1.5 eV light may not be enough to excite electrons in perovskite directly from valence band to conduction band, the tail states, thermal broadening, ultrashort pulses, and two-photon effects can make the transition possible. For convenience, we still focus on electrons at conduction band minimum of the perovskite.

For measuring charge recombination dynamics, a time-correlated single-photon-counting setup (Edinburgh F900) was applied. Film samples were photoexcited using a 485 nm laser pulse at frequencies of 2.5 MHz, with a pulse width of 0.7 ns and power of 0.77 mW. The PL light at the wavelength of 770 nm was collected using a high-resolution monochromator.

Theoretical Models and Computational Parameters. First-principles density functional theory calculations were carried out to study the geometry and electronic structure of the perovskite/TiO₂ interface. The static electronic structure and adiabatic molecular dynamics (MD) are performed with the VASP code using a plane wave basis, the PBE density functional, and the projector augmented wave (PAW) potentials. An energy cutoff of 500 eV and Γ point k-sampling are used. DFT + U calculations of Ti 3d electrons are carried out for structural optimization and interfacial dynamics. By applying reliable test of the U value in the range of 3 to 8 eV, we get band gap of 2.9 eV for TiO₂ rutile (110) surface with U = 4.2 eV and J = 0.5 eV, which agrees well with the experimental data (~3.0 eV). It should be noted that the value of U we used is only applicable in our perovskite/TiO₂ system and is not universal for other systems containing Ti atoms.

In line with the experiments, we have placed a perovskite layer on top of rutile TiO₂ (110) surface with stoichiometric composition (Figure 5a). For geometry optimization of bulk TiO₂ and perovskite, a 4 × 4 × 4 Monkhorst–Pack grid was chosen for sampling the Brillouin zone. The calculated lattice constants are a = 6.45 Å and c = 6.495 Å for bulk perovskite CH₃NH₃PbI₃; a = 4.66 Å and c = 3.00 Å for bulk rutile-TiO₂. These values are in good agreement with the corresponding experimental ones (a = 6.41 Å and c = 6.415 Å for bulk perovskite; a = 4.59 Å, and c = 2.96 Å for rutile-TiO₂). A (2 × 4) surface slab with 96 atoms in six atomic layers was used to model TiO₂, above which a perovskite sheet containing 84 atoms was included in the calculations. The thickness of the surface vacuum is ~15 Å.

After the static geometry relaxation, we bring the system temperature to 300 K with velocity rescaling. We then carry out MD simulations in the microcanonical ensemble for 1 ps with the MD time-step of 1 fs. The MD trajectory is subsequently used in the NAMD calculations. To determine interfacial electron transfer dynamics, 300 short MD trajectories—each with 100 fs long for electron injection and 150 fs long for charge recombination—are included in the ensemble average; the averaging turns out to be crucial for capturing the stochastic nature of the coupled electron–ion dynamics. For each trajectory, the TDDFT equation is integrated with a time-step of 10⁻⁹ fs. For the interfacial electron injection dynamics, the initial photoexcited state is chosen from the low-lying empty states with the largest localization on the perovskite side. On the other hand, for the electron–hole recombination dynamics, the conduction band minimum of TiO₂ is selected as the initial state for the electron while the hole is always sitting in the valence bands of the perovskite.

ASSOCIATED CONTENT
Supporting Information
The Supporting Information is available free of charge on the ACS Publications website at DOI: 10.1021/acs.chemmate.5b04019.

XRD spectra for nanocrystalline TiO₂ and compact TiO₂ layer with different V₀ densities; SEM image of perovskite nanocrystals; and time-resolved PL measurements of perovskite on different nanocrystalline substrates (PDF).

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REFERENCES


